Notice of References Cited Application/Control No. 10/584,212 Examiner ZEWDU BEYEN Applicant(s)/Patent Under Reexamination YUAN ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0006780 A1	01-2002	Bjelland et al.	455/406
*	В	US-2002/0141390 A1	10-2002	Fangman et al.	370/352
*	C	US-2002/0150083 A1	10-2002	Fangman et al.	370/352
*	D	US-2003/0058839 A1	03-2003	D'Souza, Maurice G.	370/352
*	Е	US-7,050,422 B2	05-2006	Xu et al.	370/352
*	F	US-7,146,410 B1	12-2006	Akman, Arda	709/220
*	G	US-7,200,139 B1	04-2007	Chu et al.	370/352
*	Ι	US-7,219,161 B1	05-2007	Fagundo et al.	709/245
*	I	US-7,315,888 B2	01-2008	Shibata, Atsushi	709/223
*	7	US-2009/0028146 A1	01-2009	Kleyman et al.	370/389
	K	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

	NON-I ATENI BOCOMENTO							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	х							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.